

ATTY. DOCKET NO.

4105-1

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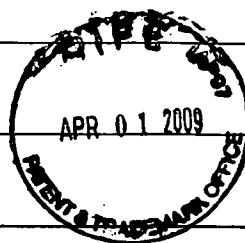
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n/a	10/568,943
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						TRANSLATION	
DOCUMENT		DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
/PWH/	1 351 939	05/1974	GB				
↓	55 139643	10/1980	JP			ABSTRACT	
	59-22250	02/1984	JP			ABSTRACT	
	63-001175	01/1988	JP			ABSTRACT	
	06-267122	09/1994	JP			ABSTRACT	
	08-212604	08/1996	JP				
	09-097457	04/1997	JP			ABSTRACT	
	09-153235	06/1997	JP			ABSTRACT	
	09-222430	08/1997	JP			ABSTRACT	
	10-334525	12/1998	JP			ABSTRACT	
	11-045467	02/1999	JP			ABSTRACT	
	11-176033	07/1999	JP			ABSTRACT	
	1 333 436	08/2003	EP				
	1 369 864	12/2003	EP				
	1 381 042	01/2004	EP				
1 398 779	03/2004	EP					
/PWH/	1 398 780	03/2004	EP				

***Examiner**

/Paul Huber/

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06/07/2009

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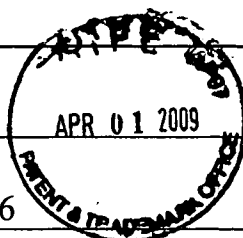
CHO et al.

FILING DATE

TC/A.U.

March 22, 2006

2627



(Use several sheets if necessary)

[illegible]

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	1 381 042	01/2004	EP					
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/PWH/	1 398 780	03/2004	EP					

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**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

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4105-74

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OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

/PWH/	Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2. (Abstract)
↓	Kazuta et al, "Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy", Journal of European Ceramic Society 21 (2001) 1581-1584. (Abstract)
↓	The Institution of Electrical Engineers, Stevenage, GB; 1 June 2002; Hiranaga et al, "Nano-sized inverted domain formation in stoichiometric LiTaO/sub3/single crystal using Scanning Nonlinear Dielectric Microscopy", XP002292217. (Abstract)
↓	Cho et al, "Scanning nonlinear dielectric microscopy with nanometer resolution", Journal of European Ceramic Society 21 (2001) 2131-2134.
↓	Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO 2001, pages 352-357.
↓	Cho et al, "Tbit/inch ² ferroelectric data storage based on scanning nonlinear dielectric microscopy", Applied Physics Letters, Vol. 81, No. 23, December 2, 2002, pages 4401-4403.
↓	Odagawa et al, "Measuring ferroelectric polarization component parallel to the surface by scanning nonlinear dielectric microscopy", Applied Physics Letters, vol. 80, No. 12, Mar. 25, 2002.
/PWH/	Matsuura et al, "Fundamental Study on Nano Domain Engineering Using Scanning Nonlinear Dielectric Microscopy", Jpn. J. Appl. Phys. vol. 40 (2001) pp. 4354-4356, Part 1, No. 6B Jun. 2001.

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